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OFGS File No: P/29-1642

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of  
ITO, Munehiro

New York, New York  
Date: January 25, 2006

Serial No.: 10/723,278

Group Art Unit: 2813

Date Filed: November 24, 2003

For: METHOD FOR TESTING SEMICONDUCTOR MEMORY DEVICE AND TEST  
CIRCUIT FOR SEMICONDUCTOR MEMORY DEVICE

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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**STATUS INQUIRY LETTER**

Sir:

We filed the above application with the U. S. Patent and Trademark Office on November 24, 2003.

As of this date, we have not received a first Office Action from the Patent Office. Kindly advise us of the status of this application.

Respectfully Submitted,

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